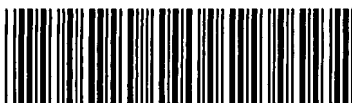


**Search Notes**

Application/Control No.

10/542,014

Examiner

Eric Elcenko

Applicant(s)/Patent under  
Reexamination

MUNETSUGU ET AL.

Art Unit

2617

**SEARCHED**

Class	Subclass	Date	Examiner

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
Same as used previously	6/25/2007	EE
Consult with Duc Nguyen on Independent Claims	6/25/2007	EE